

# Evolution of machine learning for NIF Optics Inspection (OI)

LLNL Data Science Workshop

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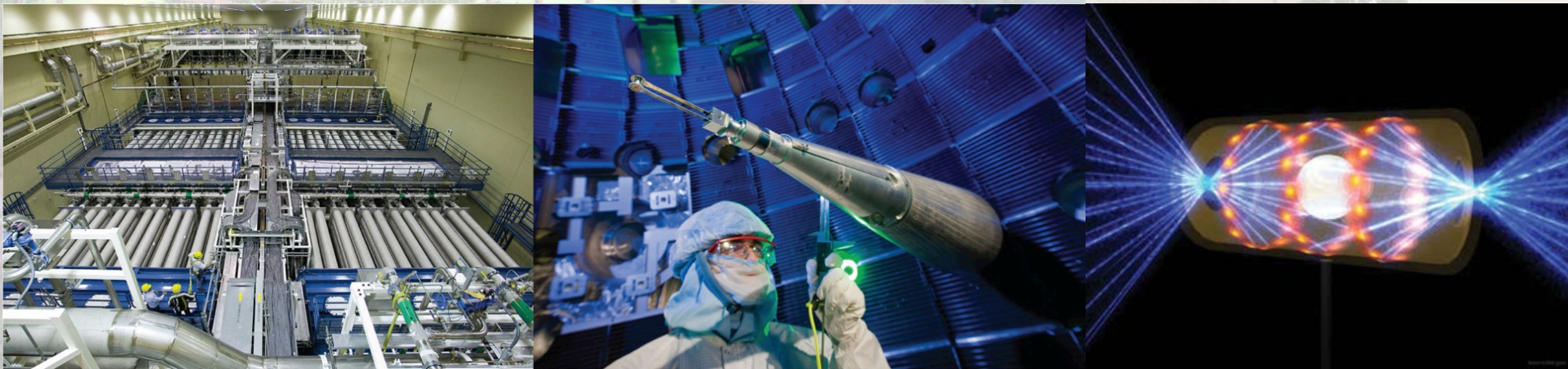
Aug 7-8, 2018





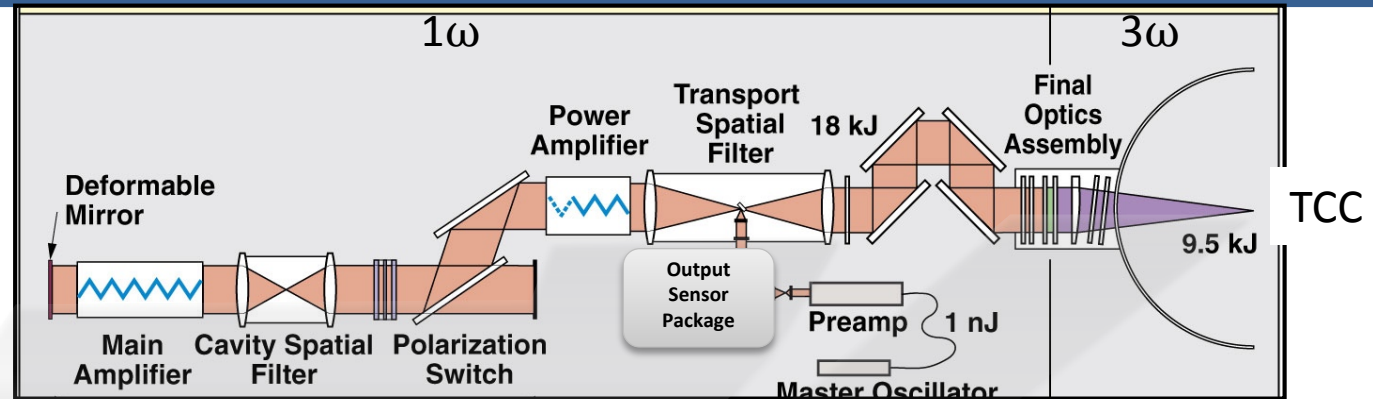
# NIF re-creates the conditions inside of stars, giant planets; it routinely operates at energies that can damage optics

- The National Ignition Facility routinely operates at 1.8 MJ (8 J/cm<sup>2</sup>), twice the fluence that damages ordinary fused silica optics
- An optics recycle loop includes identification and repair of damage sites on optics, so specialty optics can be re-used, enabling continued high fluence operation of the laser
- Automated optics inspection (OI) informs and enables an efficient recycle loop



Since 2007, we've used machine learning to improve analysis accuracy, automation and quality control to inform and enable the NIF Optics Recycle Loop.

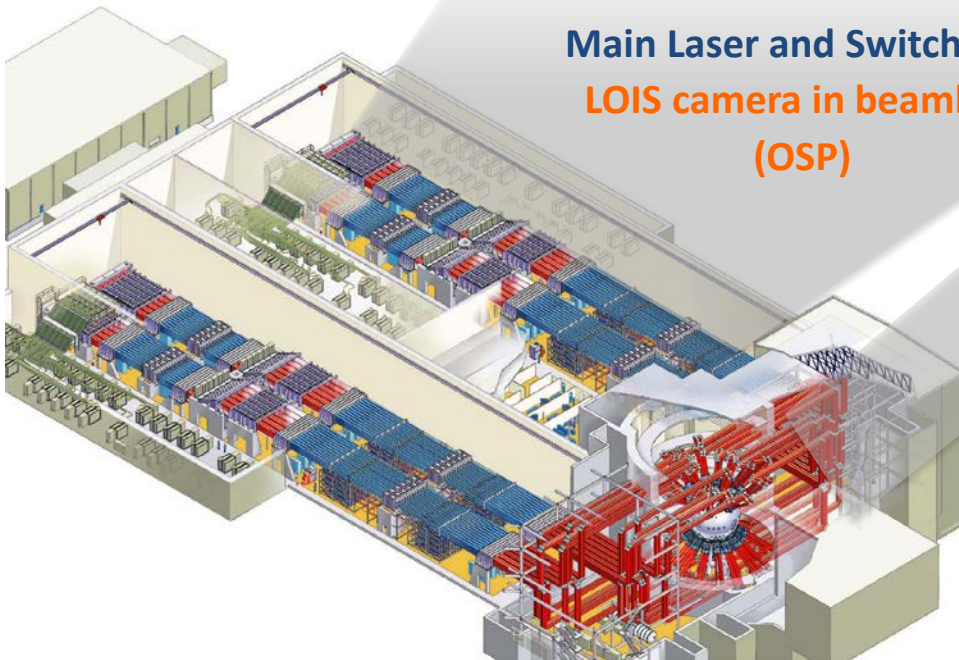
Several custom camera systems inspect optics *in situ* (on the NIF Beamline) to constantly monitor each and every damage site on thousands of optics



**Main Laser and Switchyard**  
LOIS camera in beamline  
(OSP)

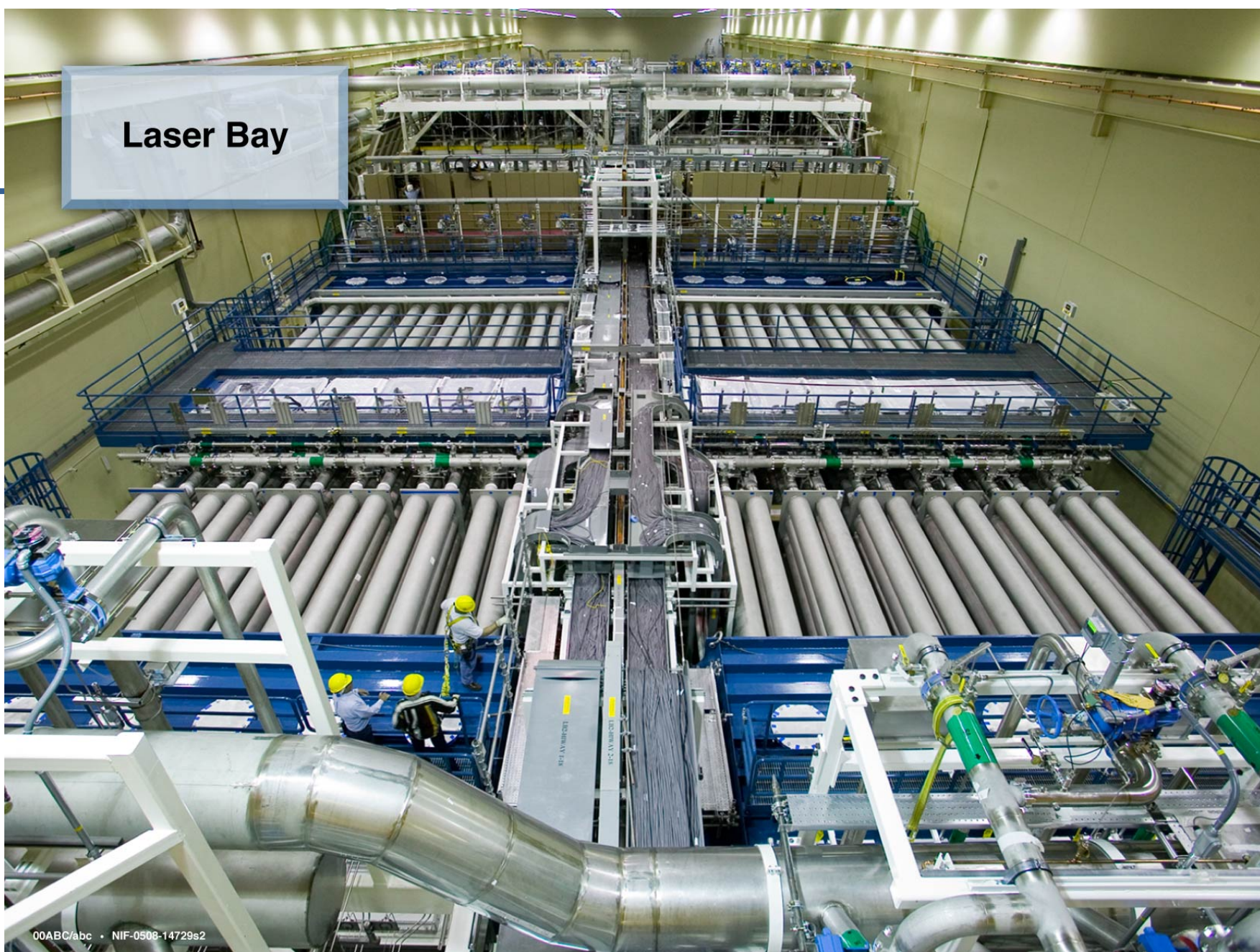
**Final Optics Damage Inspection**  
FODI camera at target chamber  
center (TCC)

**Side-Illuminated Damage Evaluation**  
SIDE camera in beamline  
Inspects TCVW





## Laser Bay

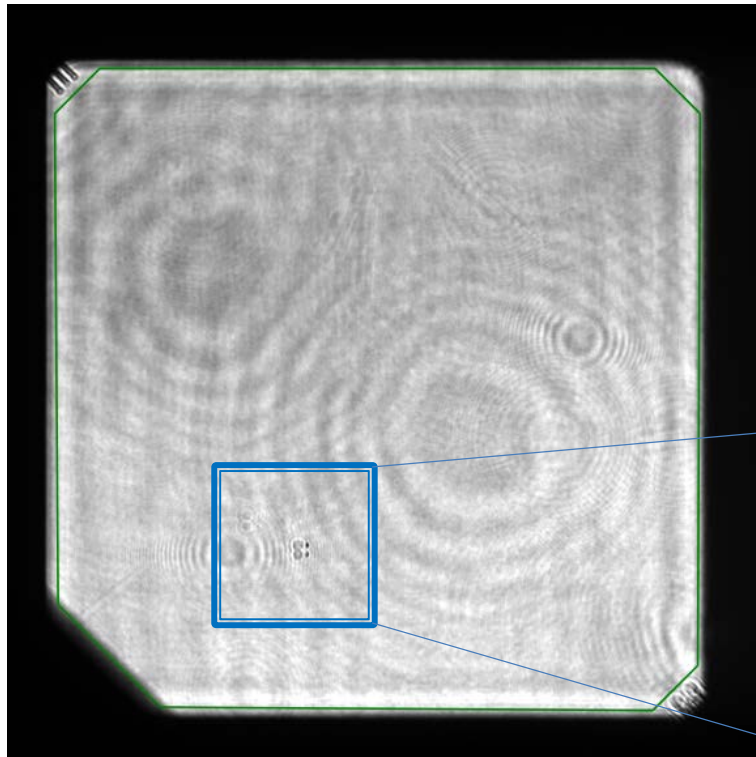


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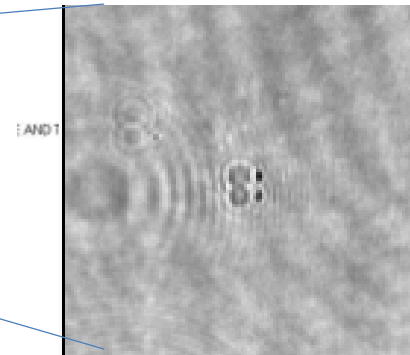
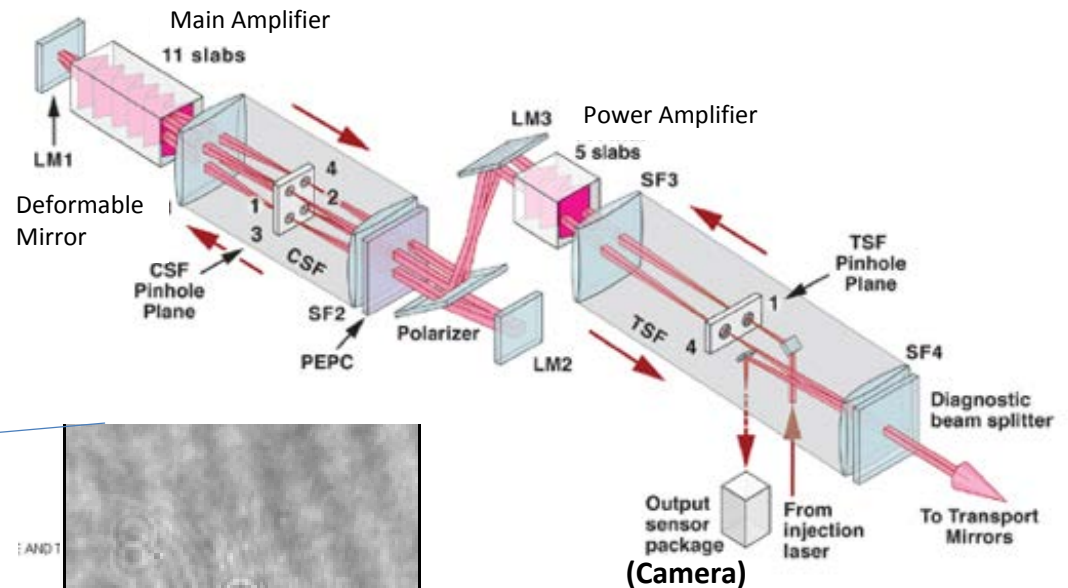




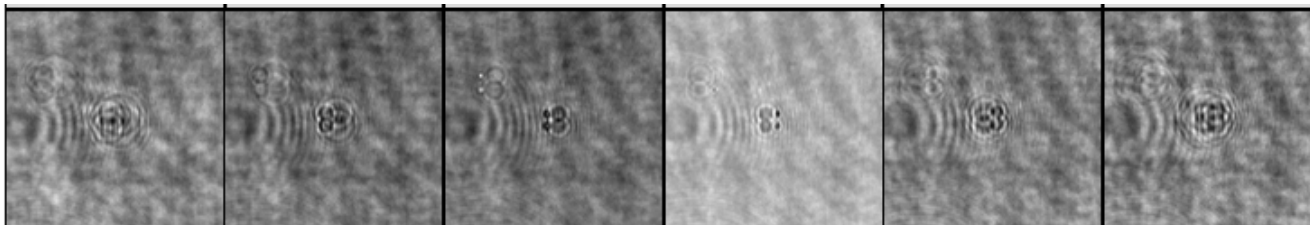
Backlit laser illumination travels through all the optics, picking up and carrying information along the way -- damage sites scatter light and leave a shadow



B266 SF3\_LowZ N180206-002-000\_180206\_104329



For 1 year (~2007) a dozen experts classified each site found.



# Supervised machine learning method, ensemble of decision trees (random forests), requires we analyze the images and extract information about the damage sites

Input a data file (text) that associates truth labels with results of analysis & feature extraction

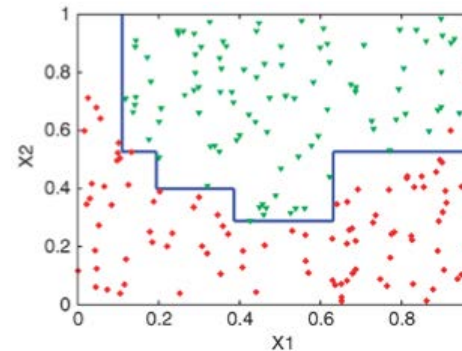
Training sample	Measurements, attributes	Expert Truth
Candidate1	Size1, OpticType1, Brightness1...	"Defect"
Candidate2	Size2, OpticType2, Brightness2...	"Camera Flaw"
Candidate3	Size3, OpticType3, Brightness3...	"Reflection"

Grow decision trees

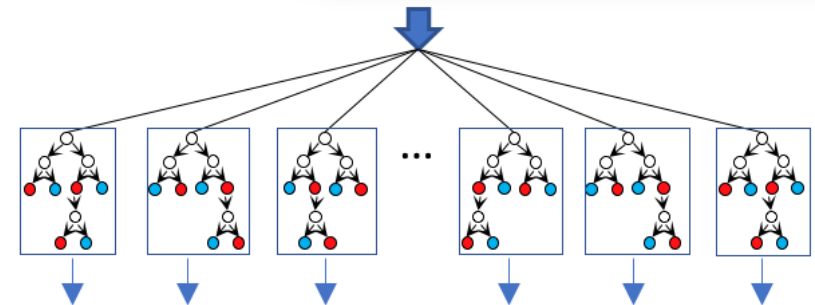
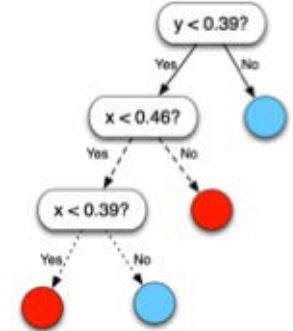
- Divide up features space with straight lines
- Use a different subset of data for each tree

Multiple trees provide a diversity of rules (partitions in feature space) and the final vote has higher accuracy than a single tree.

2-D Feature Space



Decision Tree





# Steps for applying supervised machine learning (ensemble of decision trees) to NIF main laser optics inspections

## Training phase



Experts “Log Defects”  
to train data



OI Analysis team  
collects logged defects  
and “cleans” the data



Use cleaned data to  
grow an ensemble of  
decision trees



## Test or prediction phase



Operations: Send new  
images for analysis to  
find defect candidates

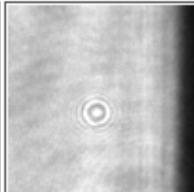
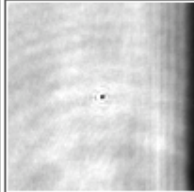
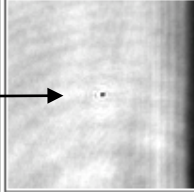
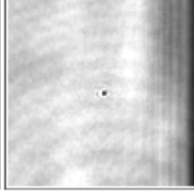
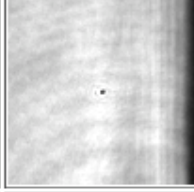


Candidates are  
“fed” to  
decision trees



Trees vote for  
predicted class

OI software tracks defects through history, so if a candidate defect was classified during any one inspection....

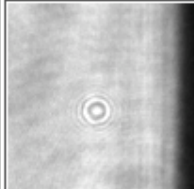
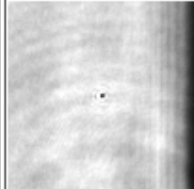
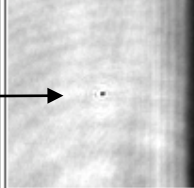
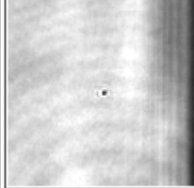
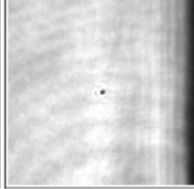
Shot Id	Image Id	Defect Name Id	Beamline	System	Defect Id	Comment Id	Classification	Thumbnail
N050719-001-999	44129	663592	314	SHOTCYCLE_SF3	697238			
N050729-001-999	44364	663592	314	SHOTCYCLE_SF3	698434			
N050801-001-999	45114	663592	314	SHOTCYCLE_SF3	703542			
N050803-002-999	45235	663592	314	SHOTCYCLE_SF3	703542			
N050804-001-999	45320	663592	314	SHOTCYCLE_SF3	703906			

1. Label as "defect" once





... we could apply the same “expert truth” label to each instance in history to get nearly 6000 data points!

Shot Id	Image Id	Defect Name Id	Beamline	System	Defect Id	Comment Id	Classification	Thumbnail
N050719-001-999	44129	663592	314	SHOTCYCLE_SF3	697238		defect	
N050729-001-999	44364	663592	314	SHOTCYCLE_SF3	698434		defect	
N050801-001-999	45114	663592	1. Label as “defect” once					
N050803-002-999	45235	663592					defect	
N050804-001-999	45320	663592	314	SHOTCYCLE_SF3	703906		defect	

2. Apply label to all

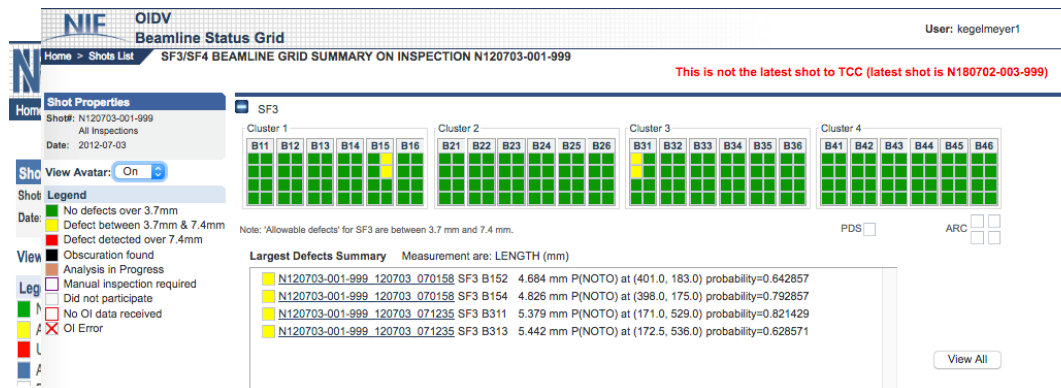
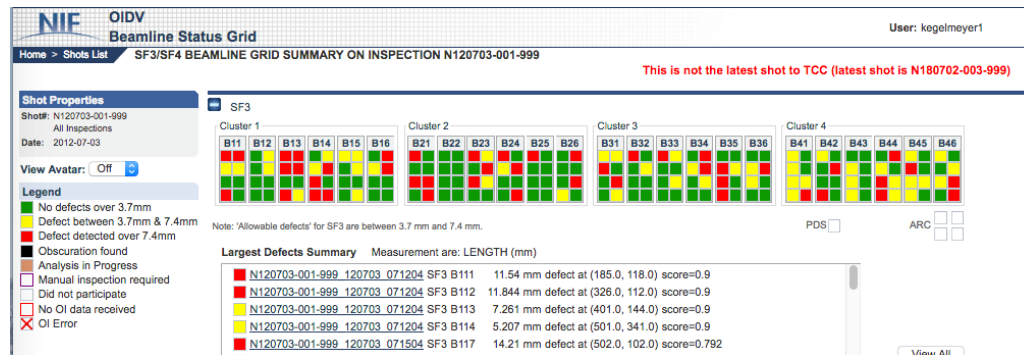


# With traditional image analysis alone, the Inspection Summary Chart had too many false alarms to follow-up within the time constraints

Before



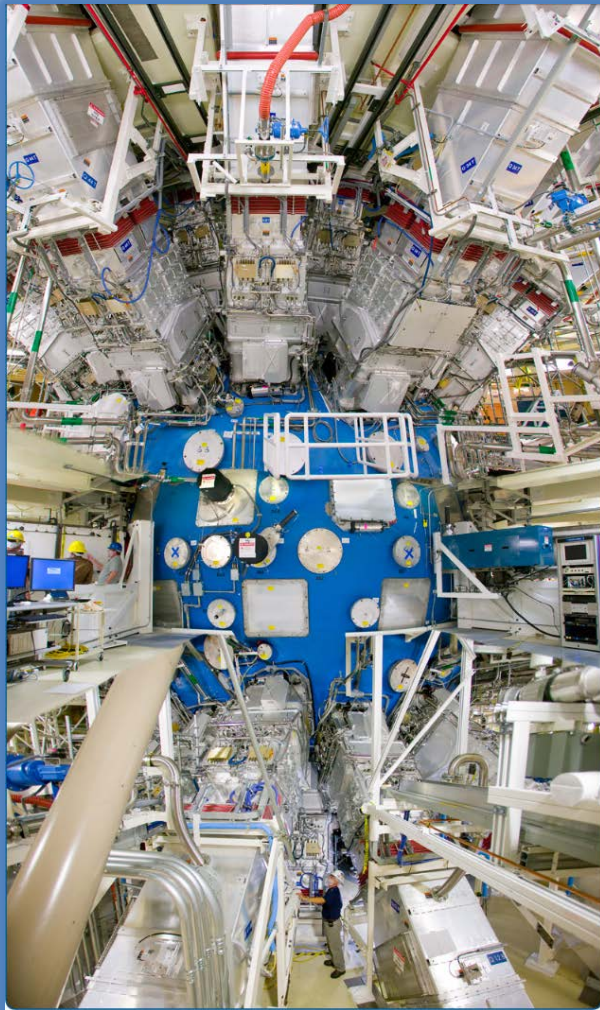
After



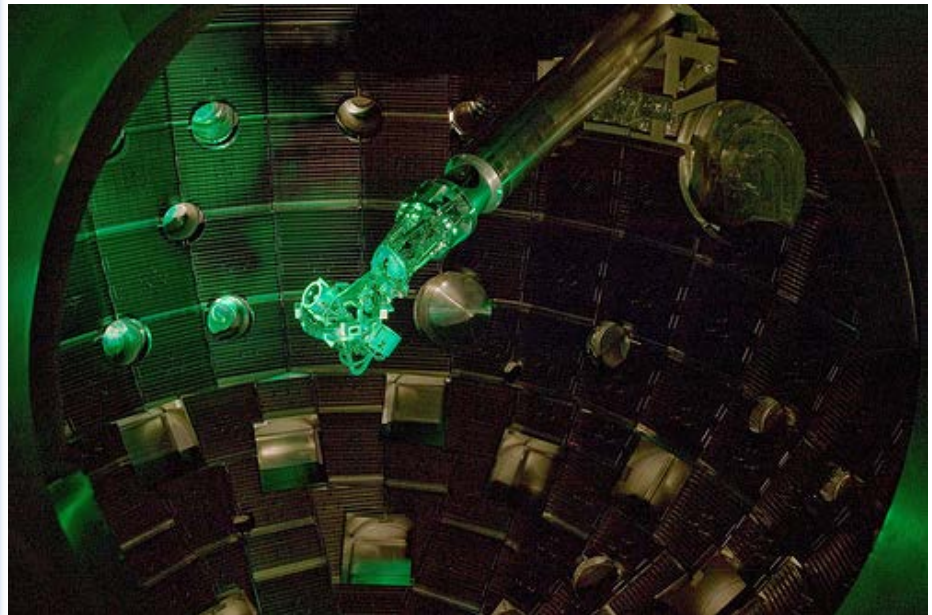
Reduction of false alarms allows operators to focus on the most relevant subset of the optics from 192 beamlines.



## The Final Optics Damage Inspection (FODI) system includes a high resolution camera on a hexapod positioner inserted at Target Chamber Center

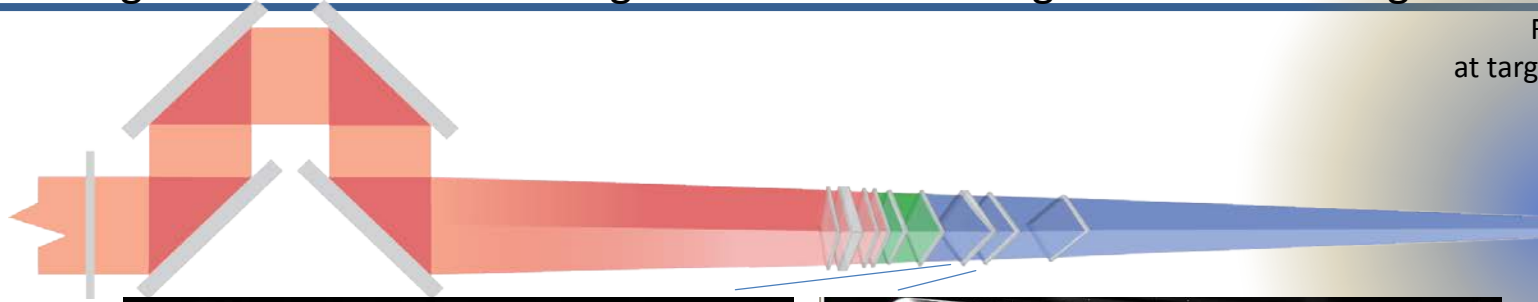


llnl-br-611652\_05.pdf-0210-183905\_seven\_wonders

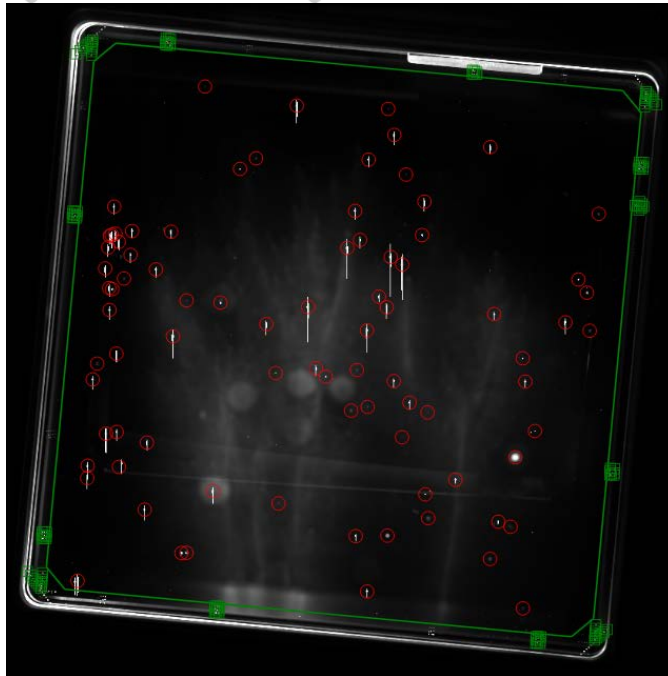
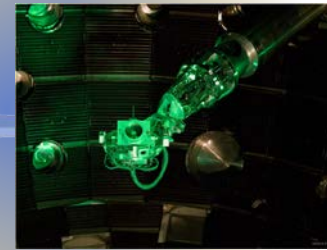


This system can image tiny damage sites (~20 microns) on optics from ~6.9 to 60 meters away (Debris Shield through LM4).

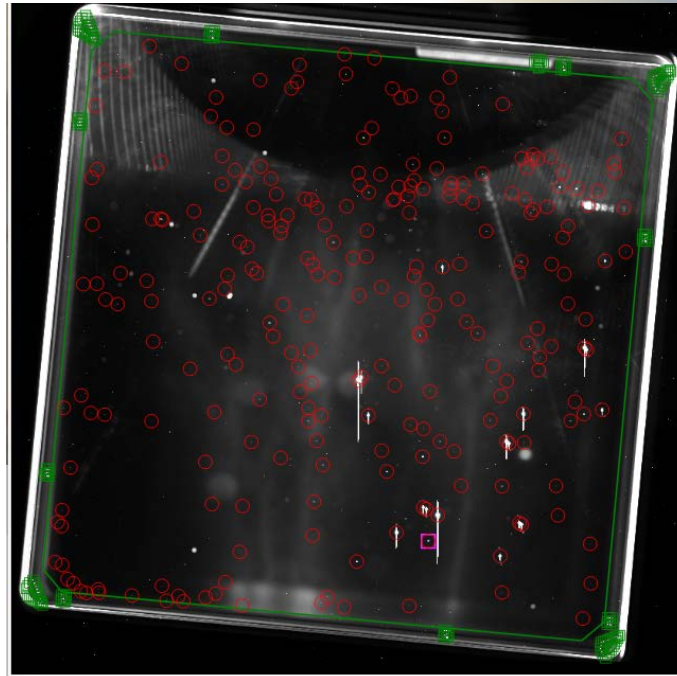
We again used ML-EDT to bring forth relevant damage sites for tracking



FODI Camera  
at target chamber center



B438-N180103-003-000\_180104\_052624 WFLC



GDS

Some detectable sites are damage/pits (actionable), while others are hardware reflections, stray/out-of-focus light, previously-repaired damage or camera flaws (not actionable)

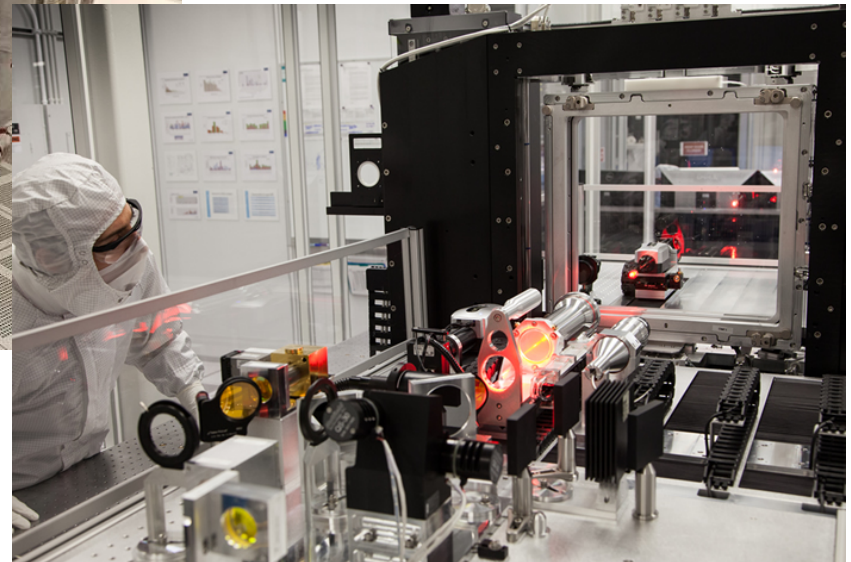


# We monitor growth of relevant sites and any approaching its optic-specific size limit is “blocked” until it can be removed and repaired

Quad	Beam	Optic Type	Optic SN	Taxon	Flaw Information							Blocker Information					Image	Growth Chart	Generate Blocker NCR 5 (5)
					Flaw Id	Observed Size (mm)	Dwg X (mm)	Dwg Y (mm)	Flaw Classification	First Seen	Last Seen	Growing?	Has Grown?	Available Blockers	NCR Number	I-Stat			
Q24B	B246	WFLF	<a href="#">272049</a>	Mod4_A2_RAM	<a href="#">10507953</a>	0.219	206.5	109.1		FODI	N120422-001-999_120423_112222	1	1		<a href="#">NULL</a>				<input type="checkbox"/>
Q24B	B247	WFLF	<a href="#">271167</a>	Mod4_A2RAM_RAM	<a href="#">3326371</a>	0.250	381.1	125.7	OMF SCRATCH, UNDAMAGED	ELV	N120422-001-999_120423_111632	1	1		<a href="#">456633</a>	4.1			<input checked="" type="checkbox"/>
Q24B	B247	WFLF	<a href="#">271167</a>	Mod4_A2RAM_RAM	<a href="#">11151729</a>	0.266	367.5	109.3	MITIGATED - RAM2000-E_4	FODI	N120422-001-999_120423_111632	1	1		<a href="#">457388</a>	4.1			<input checked="" type="checkbox"/>
Q24B	B247	WFLF	<a href="#">271167</a>	Mod4_A2RAM_RAM	<a href="#">11115471</a>	0.256	347.6	114.7	MITIGATED - RAM2000-E_4	FODI	N120422-001-999_120423_111632	1	1		<a href="#">458003</a>	4.1			<input checked="" type="checkbox"/>
Q24B	B247	WFLF	<a href="#">271167</a>	Mod4_A2RAM_RAM	<a href="#">3305757</a>	0.332	349.2	55.8	MITIGATED - RAM2000-E_4	OPL	N120422-001-999_120423_111632	1	1		<a href="#">456733</a>	4.1			<input checked="" type="checkbox"/>
Q24B	B247	WFLF	<a href="#">271167</a>	Mod4_A2RAM_RAM	<a href="#">11036678</a>	0.302	313.3	186.4	MITIGATED - RAM2000-E_4	FODI	N120422-001-999_120423_111632	1	1		<a href="#">457263</a>	4.1			<input checked="" type="checkbox"/>
Q24B	B247	WFLF	<a href="#">271167</a>	Mod4_A2RAM_RAM	<a href="#">11058819</a>	0.222	242.2	263.4		FODI	N120422-001-999_120423_111632	1	1		<a href="#">NULL</a>				<input type="checkbox"/>

Optics are removed from NIF, repaired and then re-used on NIF

# Optics are removed from NIF and brought to this Optics Mitigation Facility to repair each relevant damage site

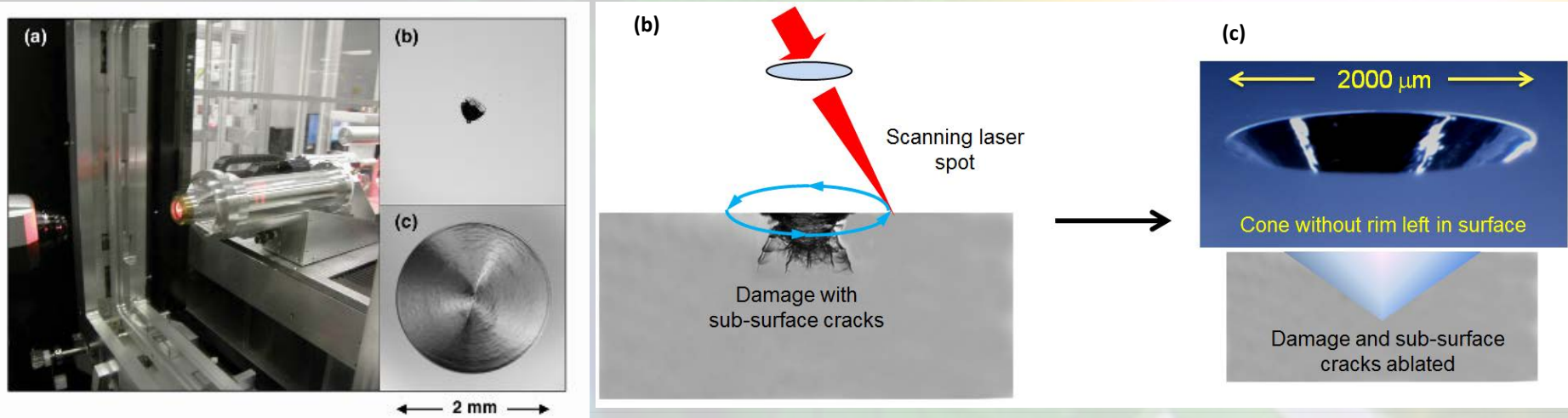




# NIF recycles optics by finding, tracking and repairing sub-millimeter damage sites

- OMF repairs sub-mm damage found on NIF optics by etching a small cone over the damage site.
- This will effectively “erase” the damage from the view of NIF’s pulsed laser light allowing it to disperse evenly.

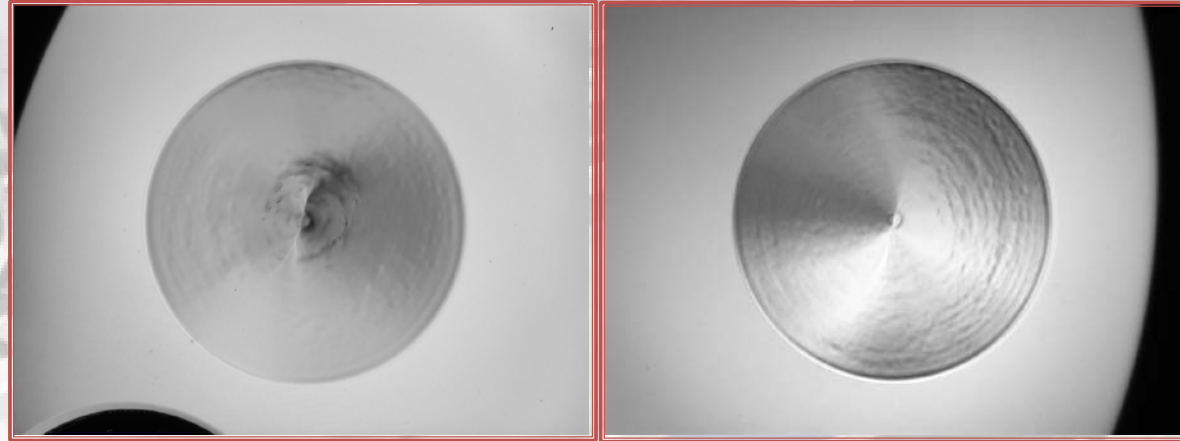
Slide by Nathan Mundhenk



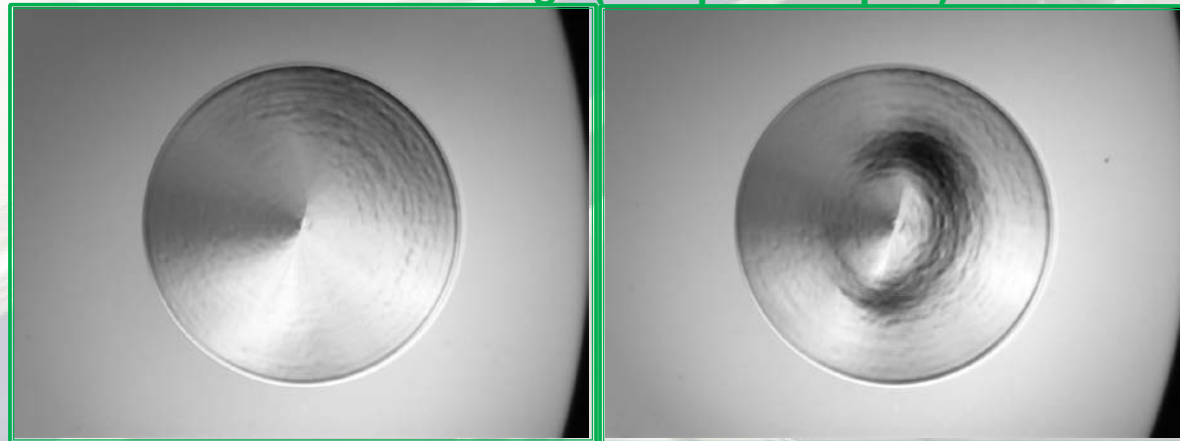
# Remnant damage was difficult-to-detect even for expert operators

- Expert operators watched a video of the entire repair process (0.3 – 5 minutes) before an image of the final repair is captured.
- The final, still image can be nearly inconclusive to the human operator without context from the video.
- In 2016 we compared machine learning methods using only the final, still image. [TN Mundhenk, LM Kegelmeyer, SK Trummer]

Remnant damage (Incomplete Repair)



No remnant damage (Complete Repair)

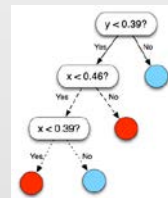


Slide by Nathan Mundhenk

# Deep Learning is a subset of Machine Learning that can automatically determine which features to use for solving the problem at hand

## Machine Learning

Feature values



Custom,  
Hand-crafted.

Sub-second

Labeled  
"truth" data.

100's

Feature  
Discovery  
& Extraction

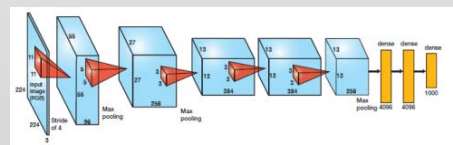
Training

Runtime  
Decision  
Making

1000's

Deep  
Learning

Machine-  
learned  
(black box)



Entire image. Many layers. Huge number of iterations. GPU-optimized.

Sub-second  
with GPU



## Transfer Learning: take a Convolutional Neural Net (CNN) model trained on a different (huge) dataset and re-tune it to work with the image dataset at hand

- ImageNet (Database): Millions of images from Google with labels Cat/Dog/Truck/Car ...
- AlexNet (Large CNN): Trained to find what distinguishes one image type from another
- DamageNet (LLNL): Modified (tuned) AlexNet to distinguish our High-Res microscopy sites

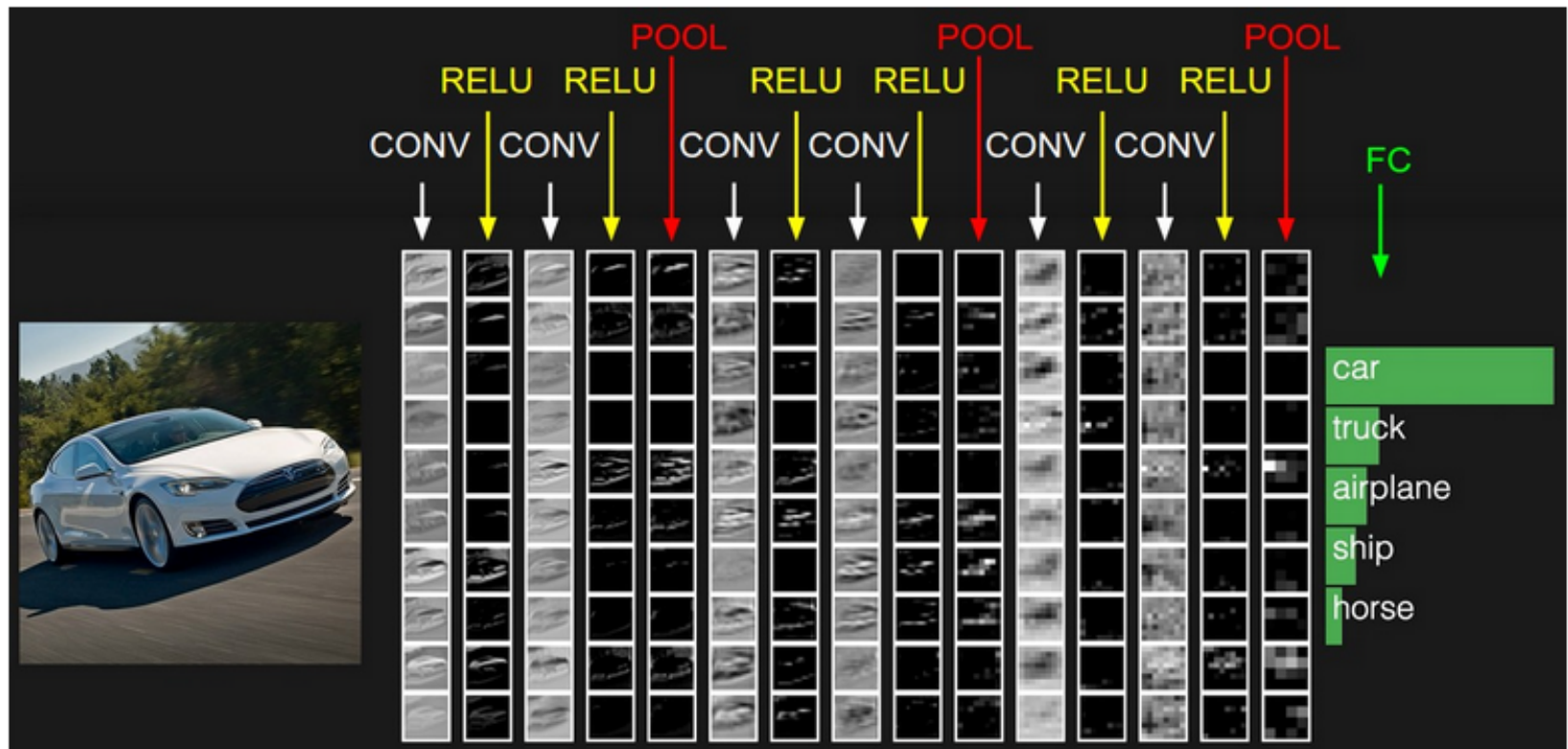
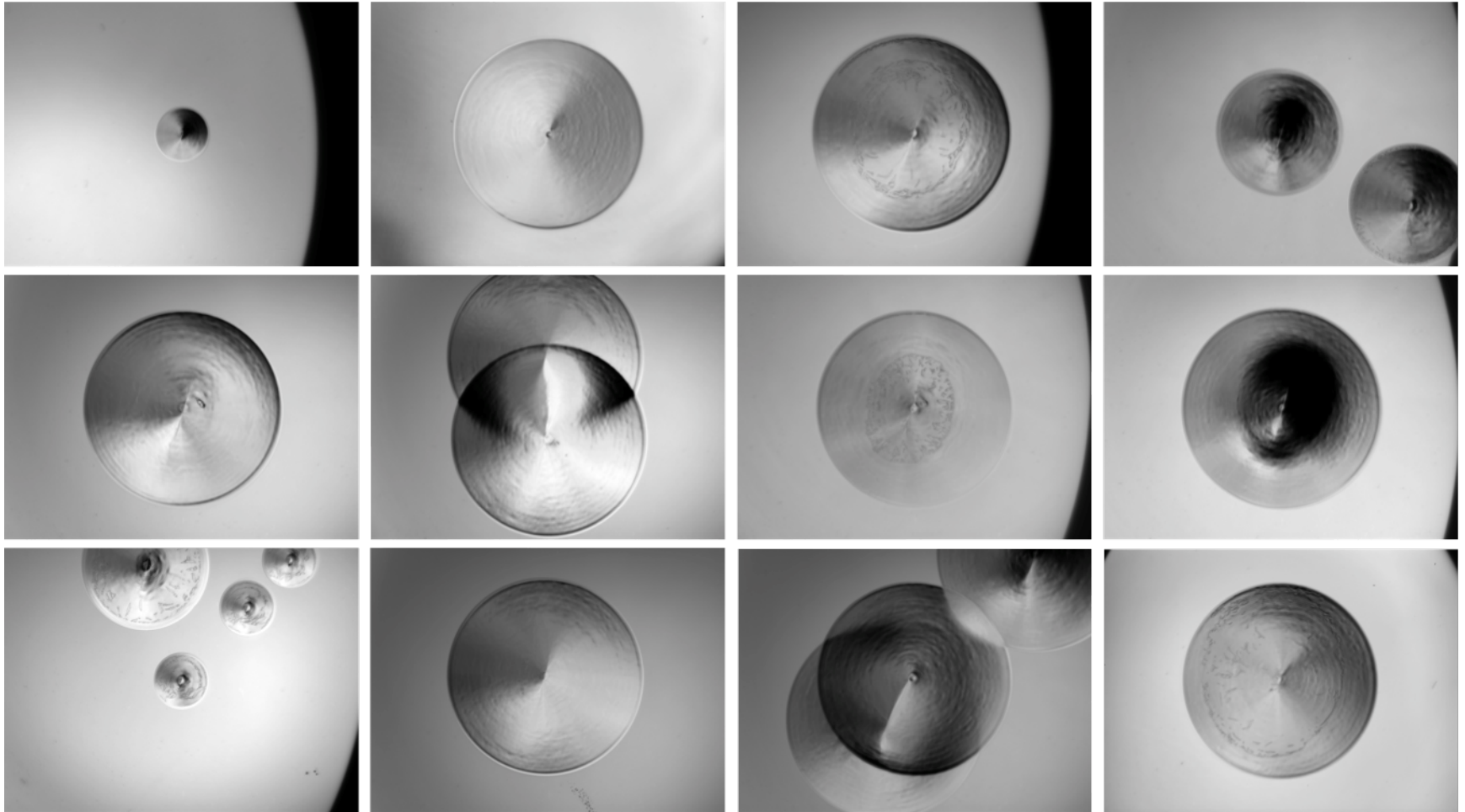


Image from Stanford Class Slides: <http://cs231n.github.io/convolutional-networks/#fc>

# The automated method must handle the subtleties of still images, as well as various repair sizes, configurations, and illuminations



Slide by Nathan Mundhenk



**We evaluated various supervised ML techniques and found likely improvement over human accuracy (estimated at ~91% worst-case)**

Method	Accuracy
Decision Trees	93.55%
AlexNet	96.86%
ResCeption	97.52%
BN-GoogLeNet	97.65%
ResNet-152	97.91%
Inception-v2	98.17%

How to be sure the Machine Learning techniques aren't "cheating"? Use visual feedback.



# Visualization of results using unsupervised feedback helped evaluate Deep Learning results

- Main idea: Rather than propagate the loss backwards through the network, we propagate the actual network output backwards.
  - This projects the output backwards to the places on the image **most responsible** for the result.
  - This is similar to how information is pushed backwards using Deep Dreams.
  - It is easy to do in *Caffe*. Just switch out the loss values in the “diff” layer with the outputs in the “data” layer and call the backwards phase function of the network.



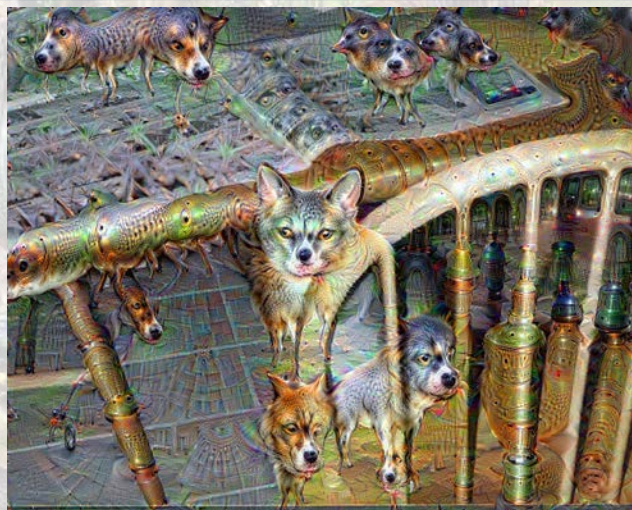
Slide by Nathan Mundhenk



# The network projection looks like its training data



Input Image



Network trained  
on *ImageNet*



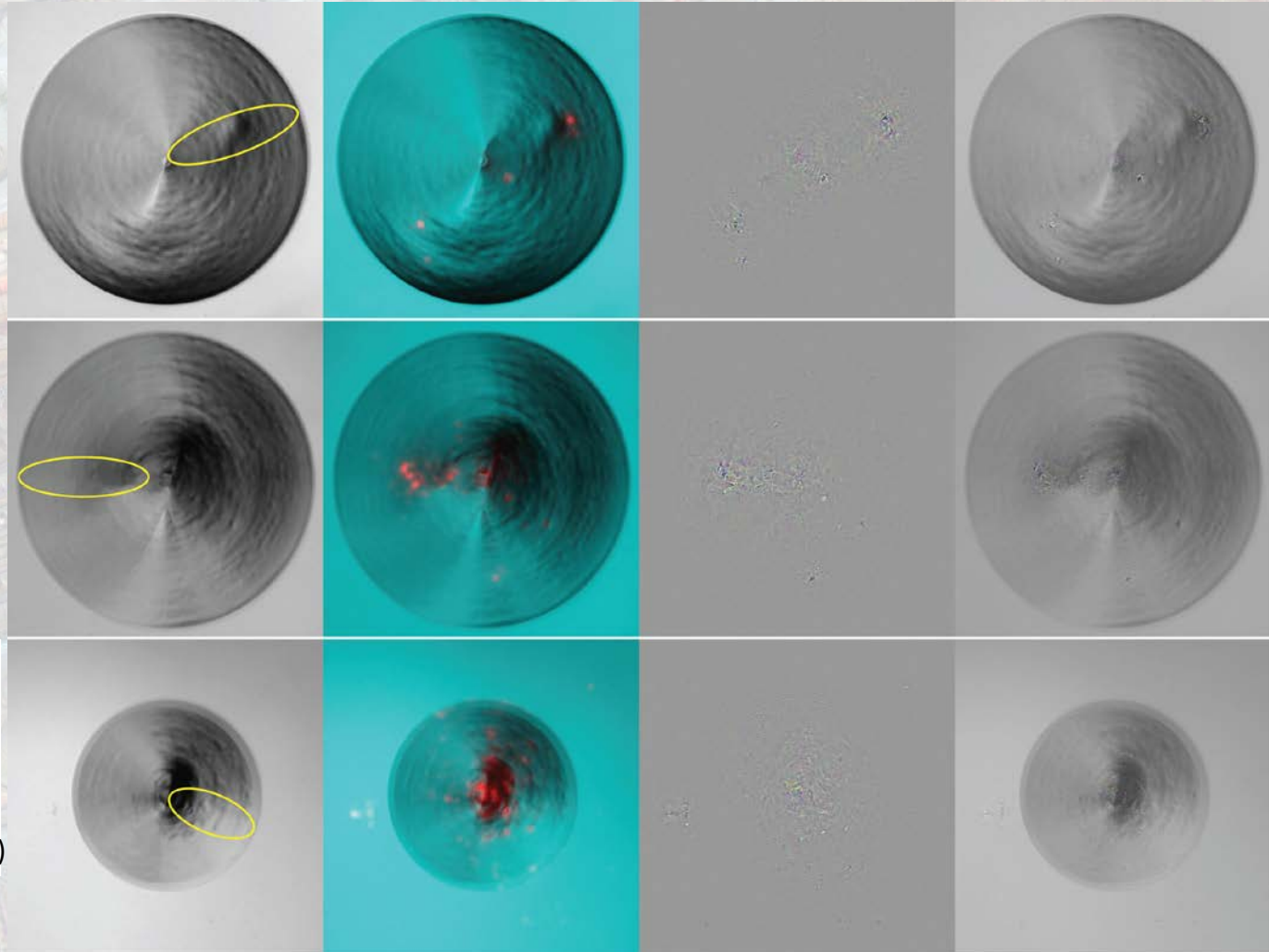
Network trained  
on *CompCars*  
(cars)

Slide by Nathan Mundhenk



# Unsupervised Results – backwards projection creates a “heat map” showing areas of focus for the neural net

- Three images selected at random with detected remnants.
- Yellow ellipse is the ground truth provided by operator.



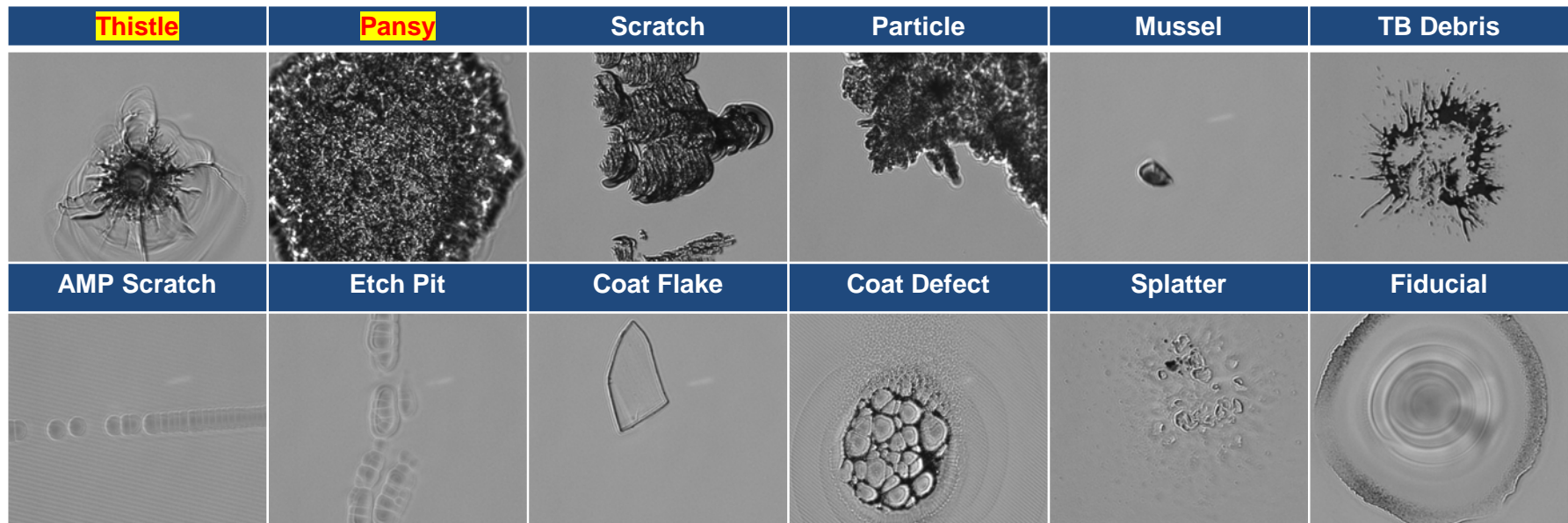
Model	Accuracy
AlexNet	96.86%
Inceptionv2	98.80% (5x cross-validation)

Slide by Nathan Mundhenk

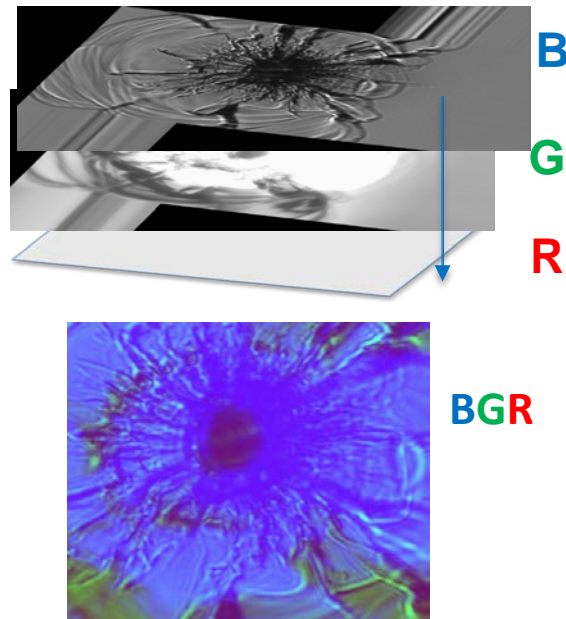


# Summer 2017: Use transfer learning to automatically classify 12 types of damage morphology from (View/Nikon) scanning microscope

- Only a small fraction of tiny sites need to be repaired.
- Automatic classification makes it feasible to repair only these.



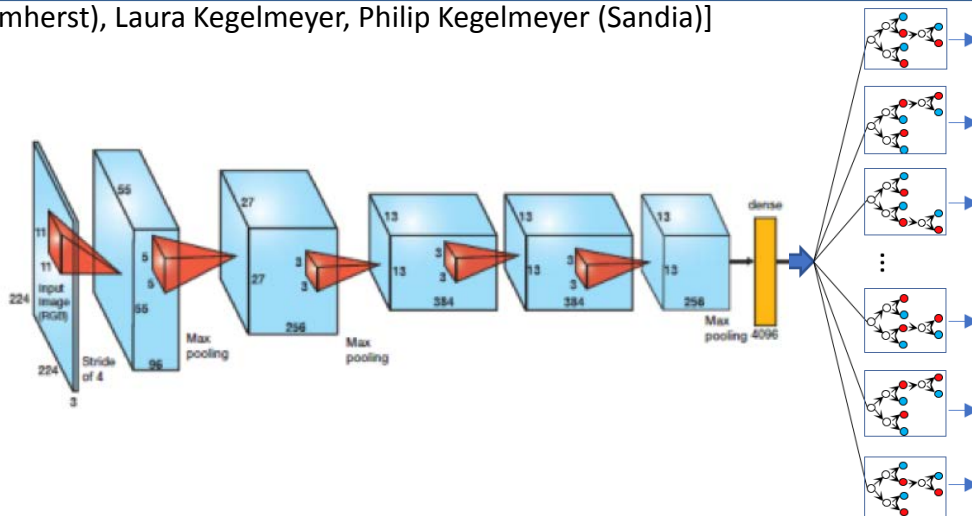
Human experts use two illuminations to classify sites. We input different modalities for our transfer learning by taking advantage of the fact that ImageNet consisted of color images.



Backlight (**B**) and Coaxial (**G**) illumination images of damage sites were concatenated into a color image (**BGR**) to prepare them for the CNN

# We improved the already-high accuracy results of two established deep learners by replacing the final decision-making layer of AlexNet with an ensemble of decision trees

[Connor Amorin (UMass Amherst), Laura Kegelmeyer, Philip Kegelmeyer (Sandia)]



Model	Image Size	Test Accuracy *5-fold cross-validation	
		12-class Damage Dataset	2-class Remnant Dataset [1]
AlexNet	352x352	*97.40%	96.86%
Inceptionv2	352x352	*98.11%	*98.80%
AlexNet + Ensemble Decision Trees	352x352	*99.17%	*99.28%



# Image analysis and machine learning for NIF Optics Inspection helps automate tedious processes and enables an efficient optics recycle loop for 1.8 MJ shots.... and beyond

- Since ~2007, machine learning, has been used to improve analysis accuracy, automation and quality control to inform and enable the NIF Optics Recycle Loop.
- Several new projects are in progress using Deep Learning and a Dual-Network solution to improve accuracy for inspection and process automation, and we have more projects in the pipeline.

